

Time	Session	Topic	Presenter
9:00 – 9:55	Opening	Welcome and Opening Introduction of new mentors Overview of the progress / status reporting	Kotaro Hasegawa, Ira Leventhal, Matthias Sauer Dirk Pflüger, Hussam Amrouch
9:55 – 10:20	Keynote	Graduate School ASIC	Jens Anders
10:20 – 10:45	Keynote	Quantum Sensors – Sensors in the Quantum Age	Vadim Vorobev
10:45 – 11:00	Break		
11:00 – 11:15	Presentation	P7: Miniaturized Millimeter-Wave RF Interface Module	Athanasios Gatzastras, Sébastien Chartier, Ingmar Kallfass
11:15 – 11:30	Presentation	P5: Automated Generation of System-Level Test Programs for Characterization of Parametric Device Properties	Denis Schwachhofer, Iliia Polian, Stefan Wagner, Steffen Becker
11:30 – 11:45	Presentation	P1: Systematic Analysis of System-Level Test Fails	Nourhan Elhamawy, Jens Anders, Iliia Polian
11:45 – 12:00	Presentation	P9: Design for Testing and Reliability in the Presence of Transistor Self-Heating for Advanced Technologies	Florian Klemme, Hussam Amrouch
12:00 – 12:15	Presentation	P10: Hyperdimensional Computing for Chip Testing – Towards Learning Fast from Little Data	Paul Genssler, Hussam Amrouch
12:15 – 13:15	Lunch Break		
13:15 – 13:30	Presentation	PA4: Online Evaluation of System Health State	Hanieh Jafarzadeh, Hans-Joachim Wunderlich
13:30 – 13:45	Presentation	P4: Secure and Privacy-Preserving Semiconductor Testing	Sebastian Hasler, Ralf Küsters
13:45 – 14:00	Presentation	P8: Software Test Suite Optimization for Complex High Data-Volume SW	Maik Betka, Steffen Becker, André van Hoorn, Stefan Wagner
14:00 – 14:15	Presentation	P3: Self-Learning Tuning for Post-Silicon Validation	Peter Domanski, Dirk Pflüger
14:15 – 14:30	Presentation	P2: Visual Analytics for Post-Silicon Validation	Andrés Zeller, Thomas Ertl, Daniel Weiskopf, Steffen Koch
14:30 – 14:45	Break		
14:45 – 14:50	Introduction	Introduction to the 2 nd Phase Projects	Dirk Pflüger
14:50 – 15:00	Short Presentation	P11: Virtual Test for Mixed-Signal Circuits: Digital Twin Based Development of Post-Silicon Tests	Thorben Schey, Michael Weyrich, Andrey Morozov
15:00 – 15:10	Short Presentation	P16: Novel Test Methods for Emerging and Classical Memories Using Magnetic Field	Munazza Sayed, Hussam Amrouch
15:10 – 15:20	Short Presentation	P12: Enhancing Test Methods by Magnetic Fields	Kartik Pandaram, Iliia Polian, Hussam Amrouch, Jens Anders
15:20 – 15:30	Short Presentation	P17: Variable Selection with Automated Feature Design and Uncertainty Estimation for Post-Silicon Validation and Production	Shuai Zhang, Bin Yang
15:30 – 15:40	Short Presentation	P14: Intelligent Sensing and On-Chip Learning for Silicon Lifecycle	Albi Mema, Jens Anders, Hussam Amrouch
15:40 – 15:50	Short Presentation	P15: Test and Reliability Challenges for Advanced Sub-5nm Technologies	Tarek Mohamed Ashraf, Hussam Amrouch
15:50 – 16:00	Short Presentation	P20: Privacy-Preserving Machine Learning for Semiconductor Testing	Marc Rivinius, Ralf Küsters
16:00 – 16:05	Pitch Presentation	P13: Over-the-Air (OTA) Production-Test Concepts for Future Millimeter-Wave Antenna Array Modules	Ali Raef, Jan Hesselbarth
16:05 – 16:10	Pitch Presentation	P19: Explanations for Failures from Software Testing	Sidra Siddiqui, Stefan Wagner, Steffen Becker
16:10 – 16:15	Pitch Presentation	P18: Automatic and Dynamic Tuning Beyond Post-Silicon Validation	Masoumeh Jafari Kaffash, Dirk Pflüger
16:15 – 17:00	Poster Session	Phase 2 Projects	
17:00 – 17:45	Keynote	Recent Trends to Use AI/ML in Semiconductor Test Segment	Ira Leventhal
17:45 – 18:00	Closing	Closing Best paper award	Matthias Sauer, Dirk Pflüger, Hussam Amrouch
18:00 –	Meet & Greet	With food and drinks	